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| Notice of References Cited | Application/Control No. 10/535,622 | | Applicant(s)/Patent Under Reexamination KNAPP ET AL. | |
| | Examiner Nitin Parekh | | Art Unit 2811 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------|----------------|
| * | A | US-6,103,803 | 08-2000 | Cheung et al. | 524/425 |
| * | B | US-5,730,922 | 03-1998 | Babb et al. | 264/258 |
| * | C | US-5,398,160 | 03-1995 | Umeda, Osamu | 361/707 |
| * | D | US-5,659,203 | 08-1997 | Call et al. | 257/778 |
| * | E | US-5,521,437 | 05-1996 | Oshima et al. | 257/701 |
| * | F | US-2003/0057573 | 03-2003 | Sekine et al. | 257/787 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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